# GenX3<sup>™</sup> 1200V IGBT w/ Diode

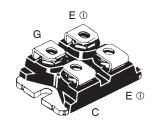
## IXGN82N120C3H1

High-Speed PT IGBT for 20-50 kHz Switching



<b>V</b> <sub>CES</sub>	=	1200V
C110	=	58A
V <sub>CE(sat)</sub>	≤	3.9V

### SOT-227B, miniBLOC E153432



G = Gate, C = Collector, E = Emitter

① either emitter terminal can be used as

Main or Kelvin Emitter

F	ea	tu	re	S

- Optimized for Low Switching Losses
- Square RBSOA
- High Current Capability
- Isolation Voltage 2500 V~
- Anti-Parallel Ultra Fast Diode
- International Standard Package

### **Advantages**

- High Power Density
- Low Gate Drive Requirement

### **Applications**

- Power Inverters
- UPS
- SMPS
- PFC Circuits
- Welding Machines
- Lamp Ballasts

Symbol	Test Conditions	5	Maximum Ratings		
V <sub>CES</sub>	$T_{J} = 25^{\circ}\text{C to } 15^{\circ}$	0°C	1200	V	
V <sub>CGR</sub>	$T_{J} = 25^{\circ}C \text{ to } 150^{\circ}$	$0^{\circ}$ C, $R_{GE} = 1M\Omega$	1200	V	
V <sub>GES</sub>	Continuous		±20	V	
V <sub>GEM</sub>	Transient		±30	V	
I <sub>C25</sub>	T <sub>c</sub> = 25°C		130	A	
I <sub>C110</sub>	$T_{\rm C} = 110^{\circ} C$		58	Α	
I <sub>F110</sub>	$T_{\rm C}^{\circ} = 110^{\circ} \rm C$		42	Α	
I <sub>CM</sub>	$T_{c} = 25^{\circ}C$ , 1ms		500	Α	
SSOA	$V_{GE} = 15V, T_{VJ} =$	125°C, R <sub>G</sub> = 3Ω	I <sub>CM</sub> = 164	A	
(RBSOA)	Clamped Inductive Load		$V_{CE} \le V_{CES}$		
P <sub>c</sub>	T <sub>C</sub> = 25°C		595	W	
T <sub>J</sub>			-55 +150	°C	
$\mathbf{T}_{JM}$			150	°C	
T <sub>stg</sub>			-55 +150	°C	
V <sub>ISOL</sub>	50/60Hz	t = 1min	2500	V~	
	$I_{ISOL} \le 1 mA$	t = 1s	3000	V~	
M <sub>d</sub>	Mounting Torque	9	1.5/13	Nm/lb.in.	
-	Terminal Connec	tion Torque	1.3/11.5	Nm/lb.in.	
Weight			30	g	

			teristic Values Typ.   Max.		
V <sub>GE(th)</sub>	$I_{C} = 1 \text{mA}, V_{CE} = V_{GE}$	3.0		5.0	V
I <sub>CES</sub>	$V_{CE} = V_{CES}$ , $V_{GE} = 0V$ , Note 1 $T_{J} = 125^{\circ}C$			50 6	μA mA
I <sub>GES</sub>	$V_{CE} = 0V, V_{GE} = \pm 20V$			±200	nΑ
V <sub>CE(sat)</sub>	$I_{\rm C}=82A,V_{\rm GE}=15V,{\rm Note}2$		3.3	3.9	V



Symbol (T <sub>1</sub> = 25°C,	SymbolTest ConditionsCharacterist $(T_{\perp} = 25^{\circ}C, \text{ Unless Otherwise Specified})$ Min.   Typ.			c Values ∣ Max.
g <sub>fs</sub>	I <sub>C</sub> = 60A, V <sub>CE</sub> = 10V, Note 2	38	62	S
C <sub>ies</sub>			7900	pF
C <sub>oes</sub>	$V_{CE} = 25V, V_{GE} = 0V, f = 1 MHz$		685	pF
C <sub>res</sub>			197	pF
$Q_{g(on)}$			340	nC
$Q_{ge}$	$I_{\rm C}$ = 82A, $V_{\rm GE}$ = 15V, $V_{\rm CE}$ = 0.5 • $V_{\rm CES}$		55	nC
Q <sub>gc</sub>			145	nC
t <sub>d(on)</sub>			30	ns
t <sub>ri</sub>	Inductive load, T <sub>J</sub> = 25°C		77	ns
E <sub>on</sub>	$I_{\rm C} = 82A, V_{\rm GE} = 15V$		5.0	mJ
t <sub>d(off)</sub>	$V_{CE} = 0.5 \cdot V_{CES}, R_{G} = 2\Omega$		194	ns
t <sub>fi</sub>	Note 3		100	ns
E <sub>off</sub>			2.5	5.0 mJ
t <sub>d(on)</sub>			32	ns
t <sub>ri</sub>	Inductive load, T <sub>J</sub> = 125°C		80	ns
E <sub>on</sub>	$I_{\rm C}=82A, V_{\rm GE}=15V$		6.8	mJ
t <sub>d(off)</sub>	$V_{CE} = 0.5 \cdot V_{CES}, R_{G} = 2\Omega$		230	ns
t <sub>fi</sub>	Note 3		270	ns
E <sub>off</sub>			4.0	mJ
R <sub>thJC</sub>				0.21 °C/W
R <sub>thCK</sub>			0.05	°C/W

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MYZ	INCHES		MILLIMETERS		
2114	MIN	MAX	MIN	MAX	
Α	1.240	1.255	31.50	31.88	
В	.307	.323	7.80	8.20	
С	.161	.169	4.09	4.29	
D E	.161	.169	4.09	4.29	
E	.161	.169	4.09	4.29	
F	.587	.595	14.91	15.11	
G	1.186	1.193	30.12	30.30	
Н	1.496	1.505	38.00	38.23	
J	.460	.481	11.68	12.22	
K	.351	.378	8.92	9.60	
L	.030	.033	0.76	0.84	
М	.496	.506	12.60	12.85	
N	.990	1.001	25.15	25.42	
0	.078	.084	1.98	2.13	
Р	.195	.235	4.95	5.97	
Q R	1.045	1.059	26.54	26.90	
	.155	.174	3.94	4.42	
S	.186	.191	4.72	4.85	
T	.968	.987	24.59	25.07	
U	002	.004	-0.05	0.1	

### **Reverse Diode (FRED)**

<b>Symbol Test Conditions</b> $(T_J = 25^{\circ}C, Unless Otherwise Specified)$			Char Min.	acteristic Typ.	Values Max.	
V <sub>F</sub>	$I_{\rm F} = 60A, V_{\rm GF} = 0V, \text{ Note 1}$				2.5	V
•	i de	$T_J = 150^{\circ}C$		1.4	1.8	V
I <sub>RM</sub>	$\begin{cases} I_{F} = 60A, V_{GE} = 0V, \\ -di_{F}/dt = 200A/\mu s, V_{R} = 300V \end{cases}$	T <sub>J</sub> = 100°C		8.3		Α
t <sub>rr</sub>	$\int -di_{F}/dt = 200A/\mu s, V_{R} = 300V$			140		ns
R <sub>thJC</sub>					0.42 °C	C/W

### Notes:

- 1. Part must be heatsunk for high-temp Ices measurement.
- 2. Pulse test,  $t \le 300\mu s$ , duty cycle,  $d \le 2\%$ .
- 3. Switching times & energy losses may increase for higher  $V_{CF}(Clamp)$ ,  $T_{I}$  or  $R_{G}$ .

### **ADVANCE TECHNICAL INFORMATION**

The product presented herein is under development. The Technical Specifications offered are derived from a subjective evaluation of the design, based upon prior knowledge and experience, and constitute a "considered reflection" of the anticipated result. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

